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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re application of: Yusuke HASHIMOTO, et al.

Serial Number: Not Yet Assigned

(§371 of International Application PCT/JP05/05469)

Filed: January 6, 2006

For: LIGHT DETECTING ELEMENT AND CONTROL METHOD OF LIGHT DETECTING ELEMENT

INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

January 6, 2006

Sir:

In compliance with 37 CFR 1.56, Applicants call to the attention of the Patent and Trademark Office the references listed on the attached PTO-1449 and cited in the enclosed international search report. References AA-AC, AE-AF and AJ are cited in the international search report.

A copy of each of the references, except for the U.S. patents and U.S. patent publication, is enclosed herewith.

In the event there are any fees due in connection with the filing of this paper, please charge Deposit Account No. 01-2340.

Respectfully submitted,
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PTO-1449	Filing Date: January 6, 2006	Group Art Unit: Not Yet Assigned	

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	AI				

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Examiner	/Marc Anthony Armand/		Date Considered	08/13/2008